

Supplementary Information

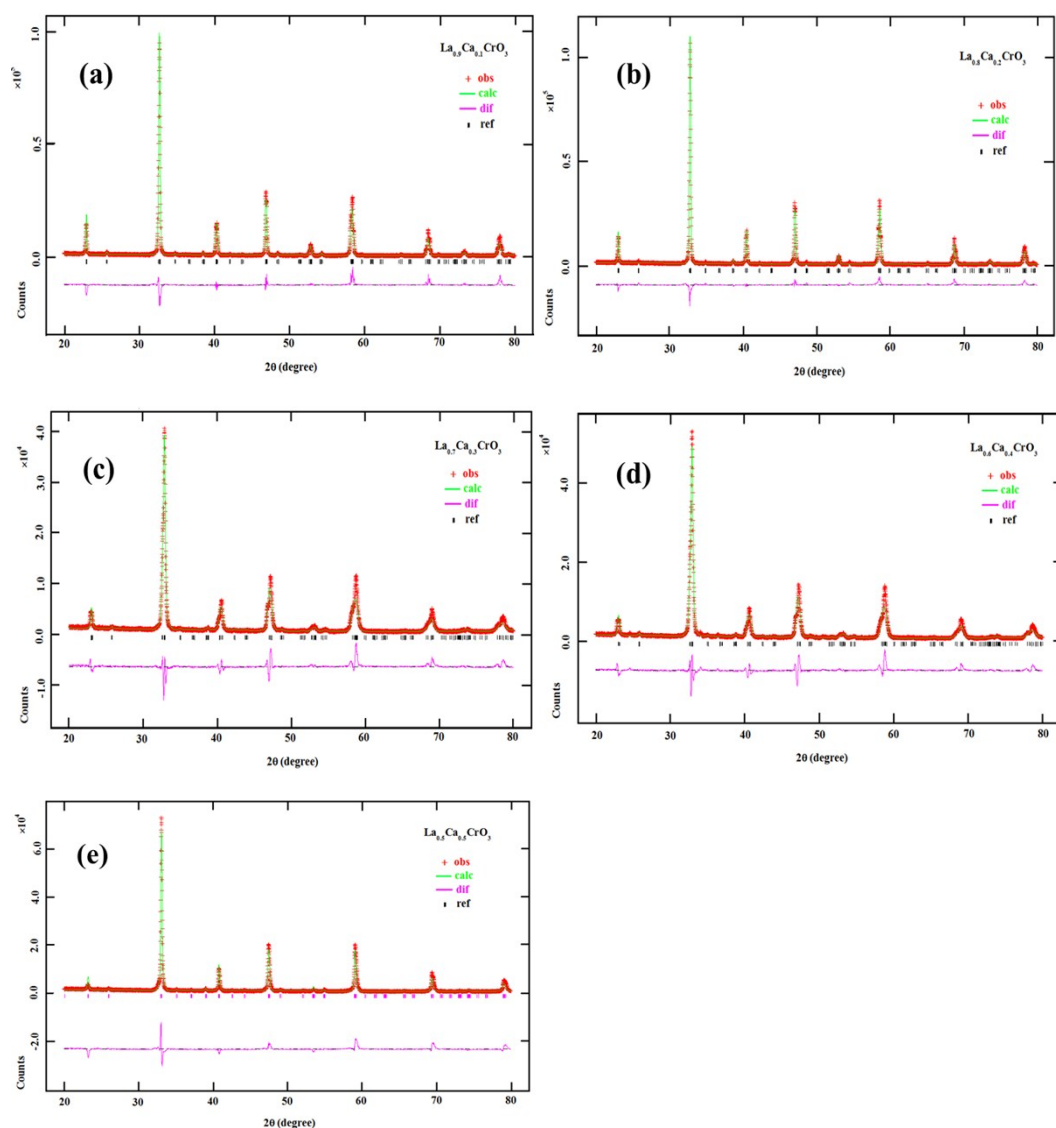


Fig.S1 Rietveld refinements (line) of the observed XRD patterns (+) for (a) $\text{La}_{0.9}\text{Ca}_{0.1}\text{CrO}_3$; (b) $\text{La}_{0.8}\text{Ca}_{0.2}\text{CrO}_3$; (a) $\text{La}_{0.7}\text{Ca}_{0.3}\text{CrO}_3$; (a) $\text{La}_{0.69}\text{Ca}_{0.4}\text{CrO}_3$; (a) $\text{La}_{0.5}\text{Ca}_{0.5}\text{CrO}_3$. Vertical bars below the patterns show the position of all possible reflection peaks of their phases. The lowest curve is the difference between the observed and the calculated intensities.

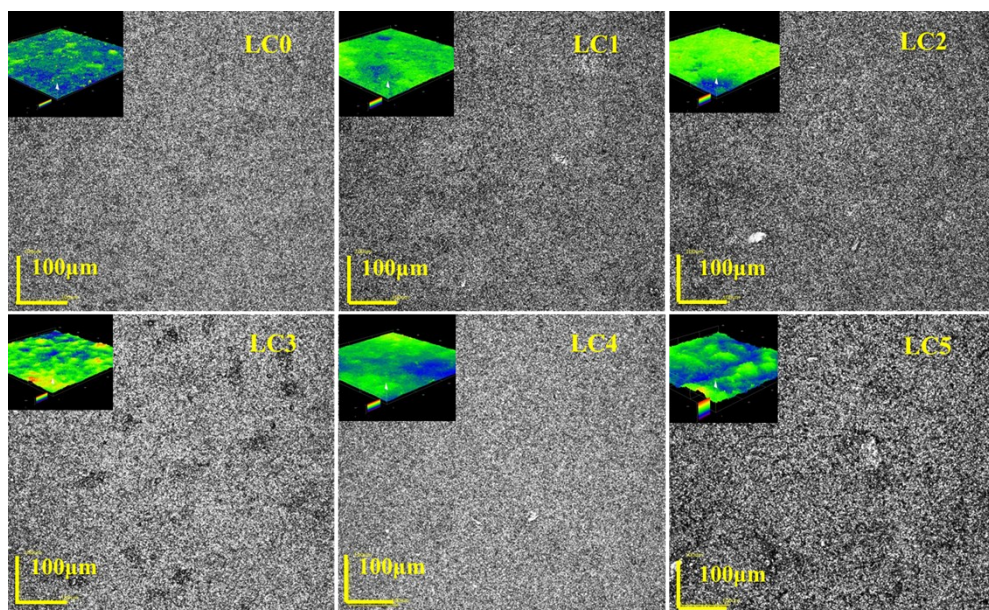


Fig.S2 Micrographs and surface roughness statistical graphs of $\text{La}_{1-x}\text{Ca}_x\text{CrO}_3$ ($0 \leq x \leq 0.5$)